



RADIO TEST REPORT

Test Report No. : 10070736H

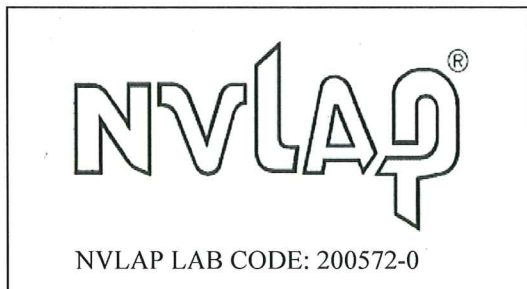
Applicant : DENSO CORPORATION
Type of Equipment : Remote Keyless Entry System (Transmitter)
Model No. : 12BDR
Test regulation : FCC Part 15 Subpart C: 2013
FCC ID : HYQ12BDR
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test: _____ October 4, 2013 _____

Representative test engineer: _____ *T. Nakagawa* _____
Tomohisa Nakagawa
Engineer of WiSE Japan,
UL Verification Service

Approved by: _____ *M. Nishiyama* _____
Masanori Nishiyama
Manager of WiSE Japan,
UL Verification Service



This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

REVISION HISTORY

Original Test Report No.: 10070736H

Revision	Test report No.	Date	Page revised	Contents
-	10070736H	October 11, 2013	-	-
(Original)				

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SECTION 1: Customer information

Company Name : DENSO CORPORATION
Address : 1-1 Showa-cho, Kariya-shi, Aichi-ken, 448-8661 Japan
Telephone Number : +81-566-61-7252
Facsimile Number : +81-566-25-4792
Contact Person : HIROMICHI HANAI

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Remote Keyless Entry System (Transmitter)
Model No. : 12BDR
Serial No. : Refer to Clause 4.2
Rating : DC 3.0V
Receipt Date of Sample : September 19, 2013
Country of Mass-production : Japan, United States of America, and China
Condition of EUT : Engineering prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: 12BDR (referred to as the EUT in this report) is the Remote Keyless Entry System (Transmitter).

General Specification

Clock frequency(ies) in the system : 8MHz (IC Clock)

Radio Specification

Radio Type : Transmitter
Frequency of Operation : 315.10MHz
Modulation : ASK (A1D)
Power Supply (radio part input) : DC 3.0V
Type of Battery : One lithium battery
Antenna type : Built-in type (Fixed)

UL Japan, Inc.

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2013, final revised on June 11, 2013 and effective July 11, 2013
Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.231 Periodic operation in the band 40.66 - 40.70MHz and above 70MHz

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements ----- IC: RSS-Gen 7.2.4	FCC: Section 15.207 ----- IC: RSS-Gen 7.2.4	N/A	N/A*1)	-
Automatically Deactivate	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators ----- IC: -	FCC: Section 15.231(a)(1) ----- IC: RSS-210 A1.1.1	N/A	Complied	Radiated
Electric Field Strength of Fundamental Emission	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators ----- IC: RSS-Gen 4.8	FCC: Section 15.231(b) ----- IC: RSS-210 A1.1.2	6.3dB 315.10MHz Horizontal PK wit Duty factor	Complied	Radiated
Electric Field Strength of Spurious Emission	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators ----- IC: RSS-Gen 4.9	FCC: Section 15.205 Section 15.209 Section 15.231(b) ----- IC: RSS-210 A1.1.2, 2.5.1 RSS-Gen 7.2.5	3.7dB 2835.900MHz Horizontal PK wit Duty factor	Complied	Radiated
-20dB Bandwidth	FCC: ANSI C63.4:2003 13. Measurement of intentional radiators ----- IC: -	FCC: Section 15.231(c) ----- IC: Reference data	N/A	Complied	Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.
*1) The test is not applicable since the EUT does not have AC Mains.

FCC 15.31 (e)

This test was performed with the New Battery (DC 3.0V) and the constant voltage was supplied to the EUT during the tests. Therefore, the EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	Complied	Radiated

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.3dB	5.0dB	5.1dB	4.9dB	5.8dB	4.4dB	4.3dB
No.2	4.3dB	5.2dB	5.1dB	5.0dB	5.7dB	4.3dB	4.2dB
No.3	4.6dB	5.0dB	5.1dB	5.0dB	5.7dB	4.5dB	4.2dB
No.4	4.8dB	5.2dB	5.0dB	5.0dB	5.7dB	5.2dB	4.2dB

*3m/1m/0.5m = Measurement distance

Radiated emission test(3m)

[Electric Field Strength of Fundamental Emission]

The data listed in this test report has enough margin, more than the site margin.

[Electric Field Strength of Spurious Emission]

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
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Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Data of EMI, Test instruments, and Test set up.

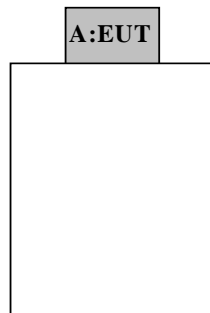
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Modes

Test Item*	Mode
Automatically Deactivate Electric Field Strength of Fundamental Emission Electric Field Strength of Spurious Emission -20dB & 99% Occupied Bandwidth	Transmitting mode (Tx), 315.10MHz
* The system was configured in typical fashion (as a customer would normally use it) for testing.	

4.2 Configuration and peripherals



* Test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Remote Keyless Entry System (Transmitter)	12BDR	001 *1) 002 *2)	DENSO CORPORATION	EUT

*1) Used for Transmitting mode

*2) Used for Normal use mode

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SECTION 5: Radiated emission (Electric Field Strength of Fundamental and Spurious Emission)

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane. The EUT was set on the center of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.
Photographs of the set up are shown in Appendix 1.

[Transmitting mode]

(Below 30MHz)

The noise level was checked by moving a search-coil (Loop Antenna) close to the EUT.

(Above 30MHz)

The Radiated Electric Field Strength has been measured on Semi anechoic chamber with a ground plane and at a distance of 3m.

The measuring antenna height was varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization.

The radiated emission measurements were made with the following detector function of the test receiver/spectrum analyzer.

Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Loop	Biconical	Logperiodic	Horn

	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz	Above 1GHz
Detector Type	Peak	Peak	Peak	Peak	Peak and Peak with Duty factor	Peak and Peak with Duty factor
IF Bandwidth	200Hz	200Hz	9.1kHz	9.1kHz	120kHz	PK: S/A:RBW 1MHz, VBW 3MHz

- The carrier level was measured at each position of all three axes X, Y and Z, and the position that has the maximum noise was determined.

Noise levels of all the frequencies were measured at the position.

*The result is rounded off to the second decimal place, so some differences might be observed.

Measurement range : 9kHz-3.2GHz
Test data : APPENDIX
Test result : Pass

SECTION 6: Automatically deactivate

Test Procedure

The measurement was performed with Electric field strength using a spectrum analyzer.

Test data : APPENDIX
Test result : Pass

SECTION 7: -20dB and 99% Occupied Bandwidth

Test Procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
20dB Bandwidth	1MHz	10kHz	30kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 % of Span	Three times of RBW	Auto	Peak *1)	Max Hold *1)	Spectrum Analyzer

*1) The measurement was performed with Peak detector, Max Hold since the duty cycle was not 100%.

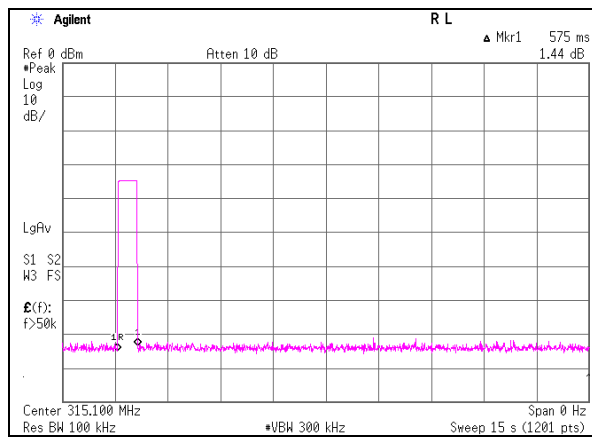
Test data : APPENDIX
Test result : Pass

APPENDIX 1: Data of EMI test

Automatically deactivate

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber
 Report No. : 10070736H
 Date : 10/04/2013
 Temperature/ Humidity : 23 deg. C / 53% RH
 Engineer : Tomohisa Nakagawa
 Mode : Transmitting 315.10 MHz

Time of Transmitting [sec]	Limit [sec]	Result
0.575	5.00	Pass



Radiated Emission (Electric Field Strength of Fundamental and Spurious Emission)

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber
Report No. 10070736H
Date 10/04/2013
Temperature/ Humidity 23 deg. C / 53% RH
Engineer Tomohisa Nakagawa
Mode Transmitting 315.10 MHz

PK

Frequency [MHz]	Detector	Reading [dBuV]		Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Duty Factor [dB]	Result [dBuV/m]		Limit [dBuV/m]	Margin [dB]		Remark Inside or Outside of Restricted Bands
		Hor	Ver					Hor	Ver		Hor	Ver	
315.100	PK	80.7	76.0	16.6	10.0	32.0	-	75.3	70.6	95.6	20.3	25.0	Carrier
630.200	PK	33.6	35.0	20.7	11.9	32.2	-	34.0	35.4	75.6	41.6	40.2	Outside
945.300	PK	28.1	35.8	25.2	13.6	31.0	-	35.9	43.6	75.6	39.7	32.0	Outside
1260.400	PK	48.3	51.2	25.1	1.9	34.2	-	41.1	44.0	75.6	34.5	31.6	Outside
1575.500	PK	48.0	53.2	25.9	2.1	33.4	-	42.6	47.8	73.9	31.3	26.1	Inside
1890.600	PK	53.2	53.5	26.6	2.3	32.9	-	49.2	49.5	75.6	26.4	26.1	Outside
2205.700	PK	57.8	56.2	27.6	2.5	32.5	-	55.4	53.8	73.9	18.5	20.1	Inside
2520.800	PK	58.5	55.5	28.7	2.7	32.4	-	57.5	54.5	75.6	18.1	21.1	Outside
2835.900	PK	56.4	51.7	29.1	2.9	32.2	-	56.2	51.5	73.9	17.7	22.4	Inside
3151.000	PK	48.1	45.6	29.4	3.0	32.1	-	48.4	45.9	75.6	27.2	29.7	Outside

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter) - Gain(Amplifier)

PK with Duty factor

Frequency [MHz]	Detector	Reading [dBuV]		Ant Factor [dB/m]	Loss [dB]	Gain [dB]	Duty Factor [dB]	Result [dBuV/m]		Limit [dBuV/m]	Margin [dB]		Remark
		Hor	Ver					Hor	Ver		Hor	Ver	
315.100	PK	80.7	76.0	16.6	10.0	32.0	-6.0	69.3	64.6	75.6	6.3	11.0	Carrier
630.200	PK	33.6	35.0	20.7	11.9	32.2	-6.0	28.0	29.4	55.6	27.6	26.2	Outside
945.300	PK	28.1	35.8	25.2	13.6	31.0	-6.0	29.9	37.6	55.6	25.7	18.0	Outside
1260.400	PK	48.3	51.2	25.1	1.9	34.2	-6.0	35.1	38.0	55.6	20.5	17.6	Outside
1575.500	PK	48.0	53.2	25.9	2.1	33.4	-6.0	36.6	41.8	53.9	17.3	12.1	Inside
1890.600	PK	53.2	53.5	26.6	2.3	32.9	-6.0	43.2	43.5	55.6	12.4	12.1	Outside
2205.700	PK	57.8	56.2	27.6	2.5	32.5	-6.0	49.4	47.8	53.9	4.5	6.1	Inside
2520.800	PK	58.5	55.5	28.7	2.7	32.4	-6.0	51.5	48.5	55.6	4.1	7.1	Outside
2835.900	PK	56.4	51.7	29.1	2.9	32.2	-6.0	50.2	45.5	53.9	3.7	8.4	Inside
3151.000	PK	48.1	45.6	29.4	3.0	32.1	-6.0	42.4	39.9	55.6	13.2	15.7	Outside

Result = Reading + Ant Factor + Loss (Cable+Attenuator+Filter) - Gain(Amplifier) + Duty factor (Refer to Duty factor data sheet)

*Other frequency noises omitted in this report were not seen or had enough margin (more than 20dB).

Duty Cycle

Test place Head Office EMC Lab. No.4 Semi Anechoic Chamber
Report No. 10070736H
Date 10/04/2013
Temperature/ Humidity 23 deg. C / 53% RH
Engineer Tomohisa Nakagawa
Mode Transmitting 315.10 MHz

Type	Times	ON time(One pulse) [ms]	ON time(in 100ms) [ms]
A	80	0.347	27.736
B	32	0.694	22.208

*1)ON time(in 100ms) = Times * ON time(One pulse)

*2)The train of pulses was exceeding 100msec, and that sampled 100msec was the worst case against the pulse train.

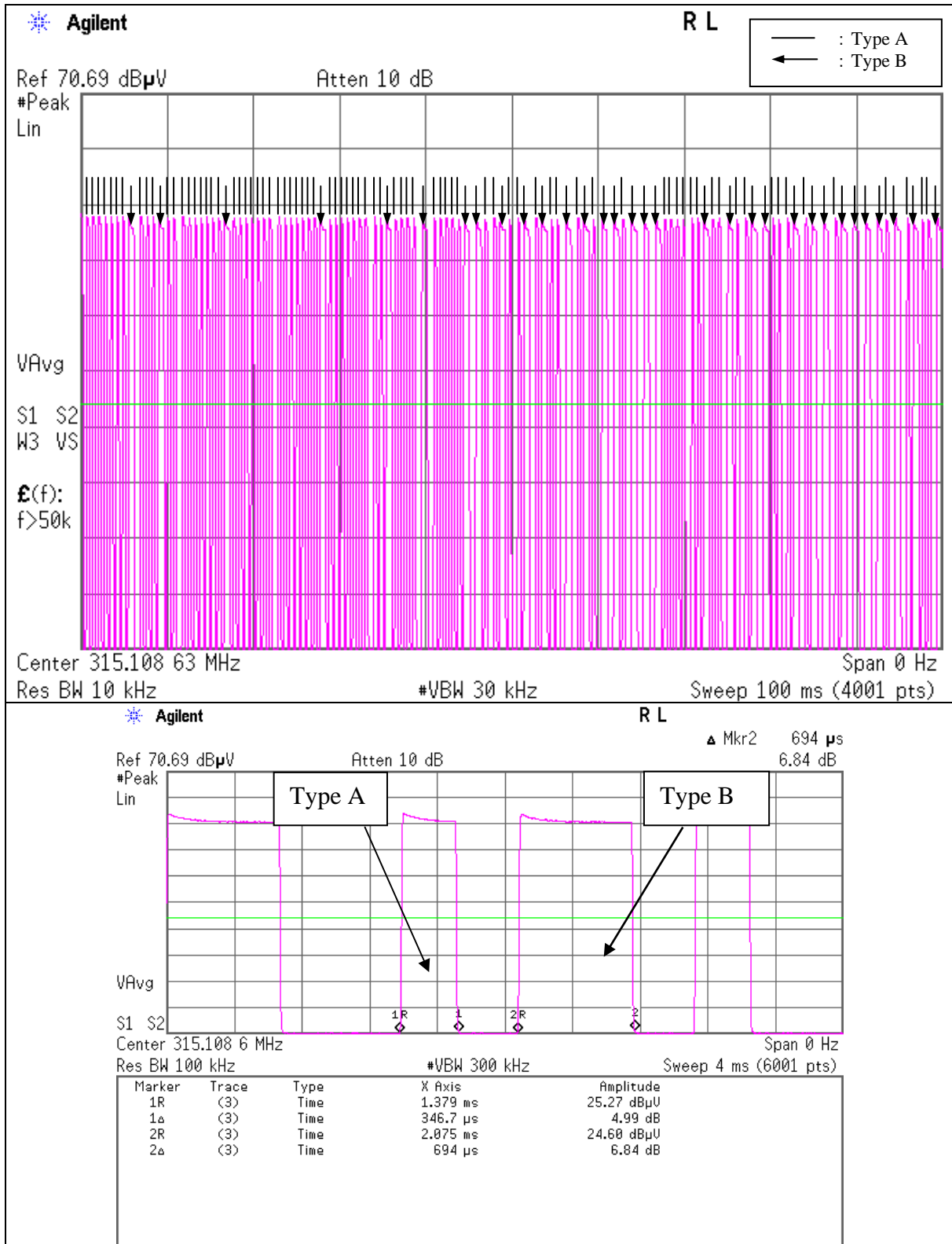
(Total)

ON time [ms]	Cycle [ms]	Duty (On time/Cycle)	Duty [dB]
49.94	100.00	0.50	-6.0

*3)ON time = Type A's ON time (in 100ms) + Type B's ON time (in 100ms)

*4)Duty = $20\log_{10}(\text{ON time}/\text{Cycle})$

Duty Cycle



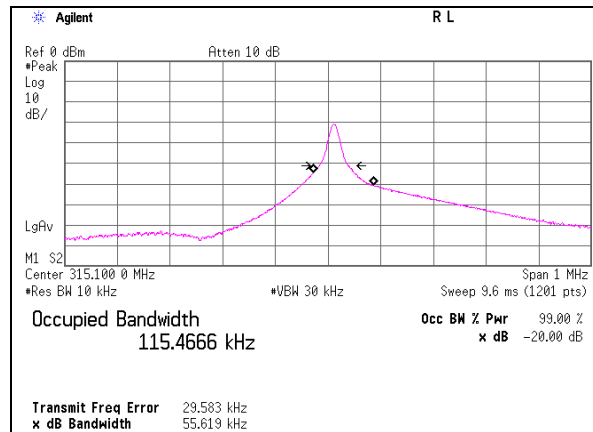
-20dB and 99% Occupied Bandwidth

Test place : Head Office EMC Lab. No.4 Semi Anechoic Chamber
 Report No. : 10070736H
 Date : 10/04/2013
 Temperature/ Humidity : 23 deg. C / 53% RH
 Engineer : Tomohisa Nakagawa
 Mode : Transmitting 315.10 MHz

Bandwidth Limit : Fundamental Frequency $315.10 \text{ MHz} \times 0.25\% = 787.75 \text{ kHz}$

-20dB Bandwidth [kHz]	Bandwidth Limit [kHz]	Result
55.62	787.75	Pass

99% Occupied Bandwidth [kHz]	Bandwidth Limit [kHz]	Result
115.47	787.75	Pass



APPENDIX 2: Test Instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE	2013/02/28 * 12
MOS-15	Thermo-Hygrometer	Custom	CTH-180	-	RE	2013/02/26 * 12
MJM-09	Measure	KDS	E19-55	-	RE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE	-
MSA-10	Spectrum Analyzer	Agilent	E4448A	MY46180655	RE	2013/02/22 * 12
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	RE	2013/04/10 * 12
MBA-05	Biconical Antenna	Schwarzbeck	BBA9106	1302	RE	2012/11/18 * 12
MLA-08	Logperiodic Antenna	Schwarzbeck	UKLP9140-A	N/A	RE	2012/11/18 * 12
MCC-50	Coaxial Cable	UL Japan	-	-	RE	2013/06/18 * 12
MAT-68	Attenuator	Anritsu	MP721B	6200961025	RE	2012/11/21 * 12
MPA-14	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2013/03/12 * 12
MHA-21	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	9120D-557	RE	2013/08/12 * 12
MCC-141	Microwave Cable	Junkosha	MWX221	1305S002R(1m) / 1204S062(5m)	RE	2013/05/28 * 12
MPA-12	MicroWave System Amplifier	Agilent	83017A	MY39500780	RE	2013/03/19 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

RE: Radiated emission, 99% Occupied Bandwidth, -20dB bandwidth , Automatically deactivate and Duty cycle tests

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